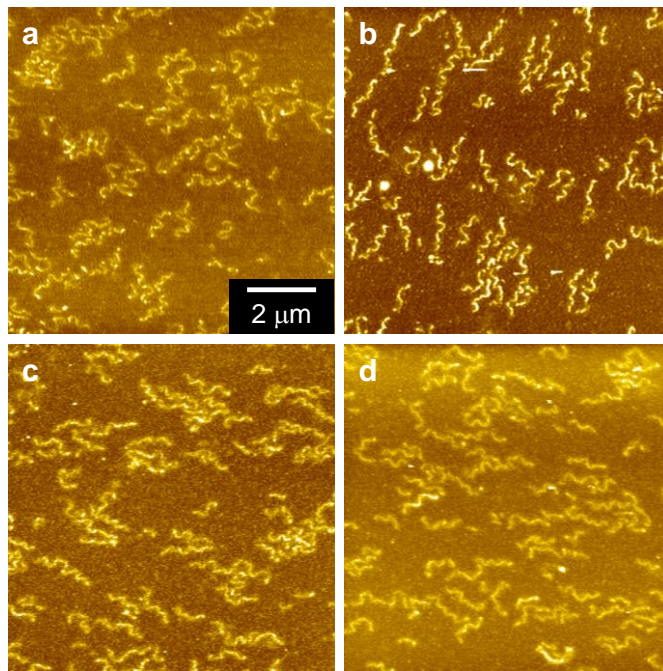


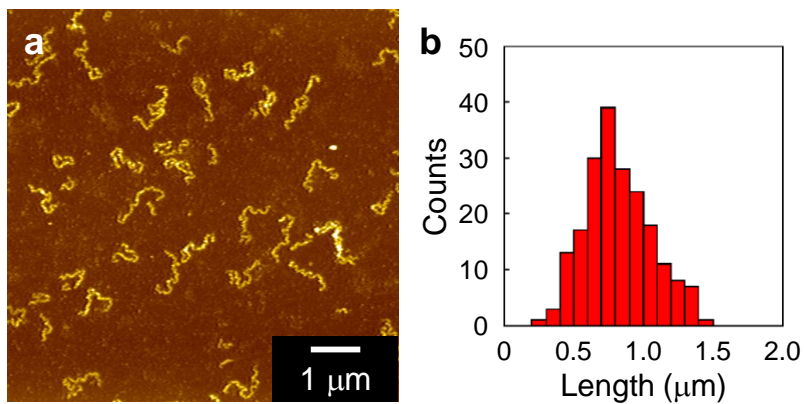
**Supplementary Figure 1. Structural analysis of HSA nanowires.**

Circular dichroism of (a) HSA and (b) HSA nanowires in PBS. (c) FTIR-ATR spectra of the HSA and HSA nanowires on Si wafer in the region of 1800–1200  $\text{cm}^{-1}$ .



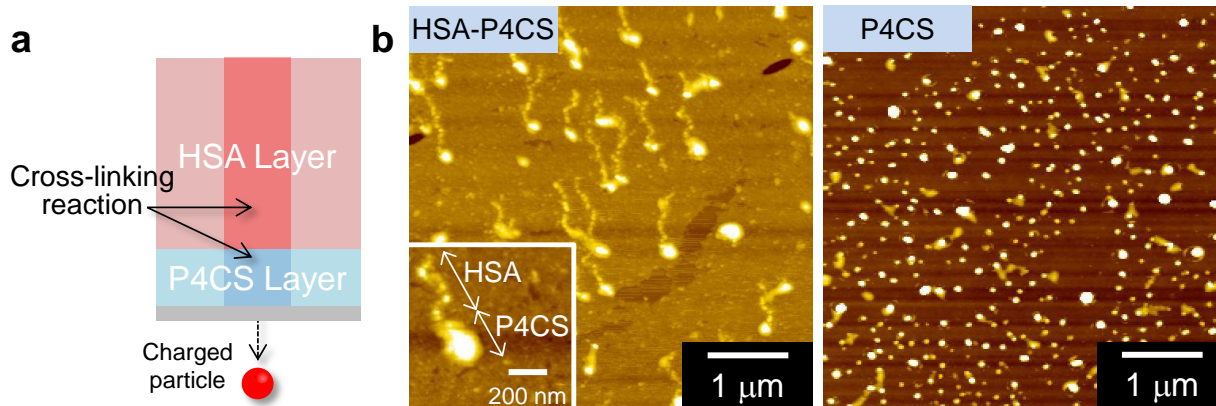
**Supplementary Figure 2. Stability of HSA nanowires.**

AFM images of HAS nanowires (a) prepared freshly and (b) after three months in the atmosphere, followed by immersing into PBS for (c) 6 hours and (d) 12 hours at 25 °C.



**Supplementary Figure 3. Effect of the thickness of the film on the fabrication of HSA nanowires with high aspect ratio.**

(a) AFM image and (b) length distribution of the HSA nanowires formed by irradiation of a 1.0 μm-thick HSA spin-coated film with a 490 MeV  $^{192}\text{Os}^{30+}$  ion beam at a fluence of  $1.0 \times 10^8$  ions  $\text{cm}^{-2}$ .



**Supplementary Figure 4. Fabrication of HSA-P4CS connected nanowires.**

(a) Schematic image showing the formation of HSA-poly(4-chlorostyrene) (P4CS) connected nanowires by SPNT from an HSA (upper) and P4CS (lower) bilayer film. (b, left) AFM image of the HSA-P4CS connected nanowires fabricated by exposure to a 490 MeV  $^{192}\text{Os}^{30+}$  ion beam at a fluence of  $1.0 \times 10^8$  ions  $\text{cm}^{-2}$ . (b, right) AFM image of the P4CS nanodots formed by irradiation of a 90 nm-thick P4CS spin-coated film with a 490 MeV  $^{192}\text{Os}^{30+}$  ion beam at a fluence of  $1.0 \times 10^9$  ions  $\text{cm}^{-2}$ .